查询TIBPAL16L8-5C供应商IBPAL16L8-5C, TIBPAL16R4-5Q;PTBPAL16R6-5C加利BBAL16R8-5C TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X™ PAL® CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

- High-Performance Operation: fmax (no feedback) TIBPAL16R' -5C Series . . . 125 MHz Min TIBPAL16R' -7M Series . . . 100 MHz Min fmax (internal feedback) TIBPAL16R' -5C Series ... 125 MHz Min TIBPAL16R' -7M Series . . . 100 MHz Min fmax (external feedback) TIBPAL16R' -5C Series . . . 117 MHz Min TIBPAL16R' -7M Series ... 74 MHz Min **Propagation Delay** TIBPAL16L8-5C Series ... 5 ns Max TIBPAL16L8-7M Series . . . 7 ns Max TIBPAL16R' -5C Series (CLK-to-Q) ... 4 ns Max TIBPAL16R '-7M Series (CLK-to-Q) ... 6.5 ns Max
- Functionally Equivalent, but Faster than, Existing 20-Pin PLDs
- Preload Capability on Output Registers Simplifies Testing
- Power-Up Clear on Registered Devices (All Register Outputs are Set Low, but Voltage Levels at the Output Pins Go High)
- Package Options Include Both Plastic and Ceramic Chip Carriers in Addition to Plastic and Ceramic DIPs
- Security Fuse Prevents Duplication

DEVICE	I INPUTS	3-STATE O OUTPUTS		
'PAL16L8	10	2	0	6
'PAL16R4	8	0	4 (3-state buffers)	4
'PAL16R6	8	0	6 (3-state buffers)	2
'PAL16R8	8	0	8 (3-state buffers)	0

description

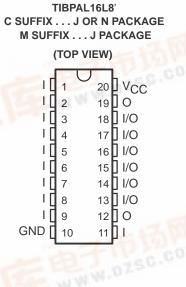
These programmable array logic devices feature high speed and functional equivalency when compared with currently available devices. These IMPACT-X[™] circuits combine the latest Advanced Low-Power Schottky technology with proven titanium-tungsten fuses to provide reliable, high-performance substitutes for conventional TTL logic. Their easy programmability allows for quick design of custom functions and typically results in a more compact circuit board.

The TIBPAL16' C series is characterized from 0°C to 75°C. The TIBPAL16' M series is characterized for operation over the full military temperature range of –55°C to 125°C.



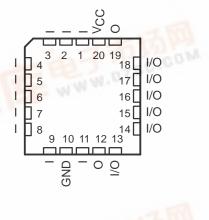
These devices are covered by U.S. Patent 4,410,987. IMPACT-X is a trademark of Texas Instruments Incorporated. PAL is a registered trademark of Advanced Micro Devices Inc.





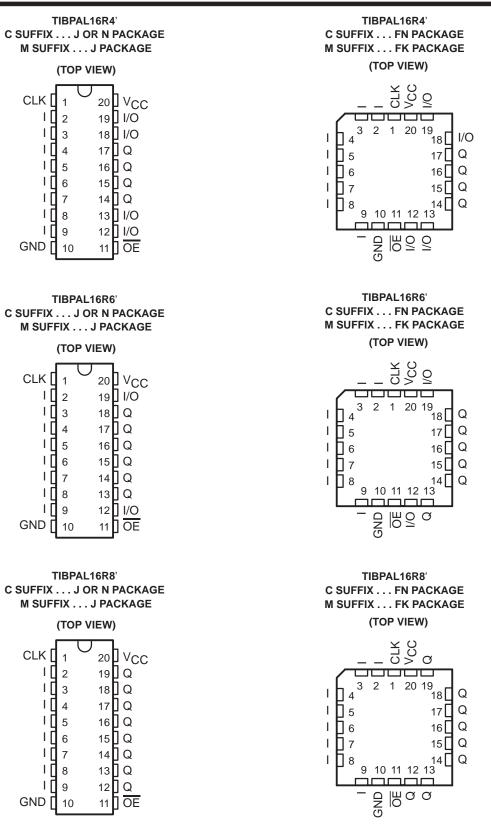
TIBPAL16L8' C SUFFIX . . . FN PACKAGE M SUFFIX . . . FK PACKAGE





Pin assignments in operating mode

TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-XTM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

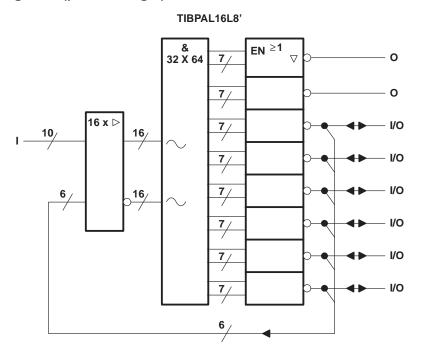


Pin assignments in operating mode

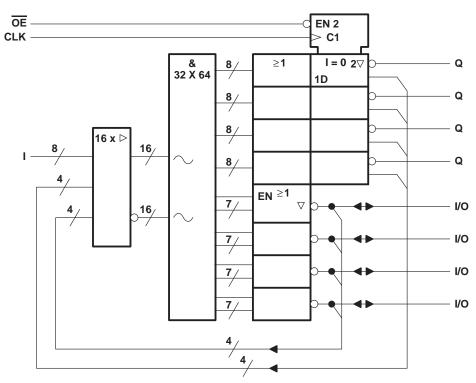


TIBPAL16L8-5C, TIBPAL16R4-5C TIBPAL16L8-7M, TIBPAL16R4-7M HIGH-PERFORMANCE IMPACT-X TM PAL® CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

functional block diagrams (positive logic)



TIBPAL16R4'



 \bigcirc denotes fused inputs



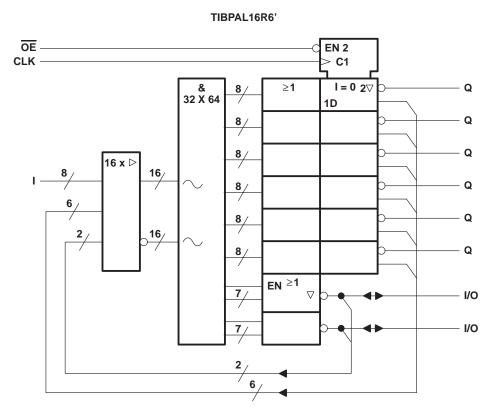
TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X TM PAL® CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

functional block diagrams (positive logic)

OE

1 -

CLK



EN 2 > C1 & 32 X 64 l = 0 2∇ 8_ ≥1 1D 8/ 8/ 16 x ⊳ 8 **16**/ <u>8</u>_ 8/ 8 16/ 8/

Q

Q

Q

Q

Q

- Q

- Q

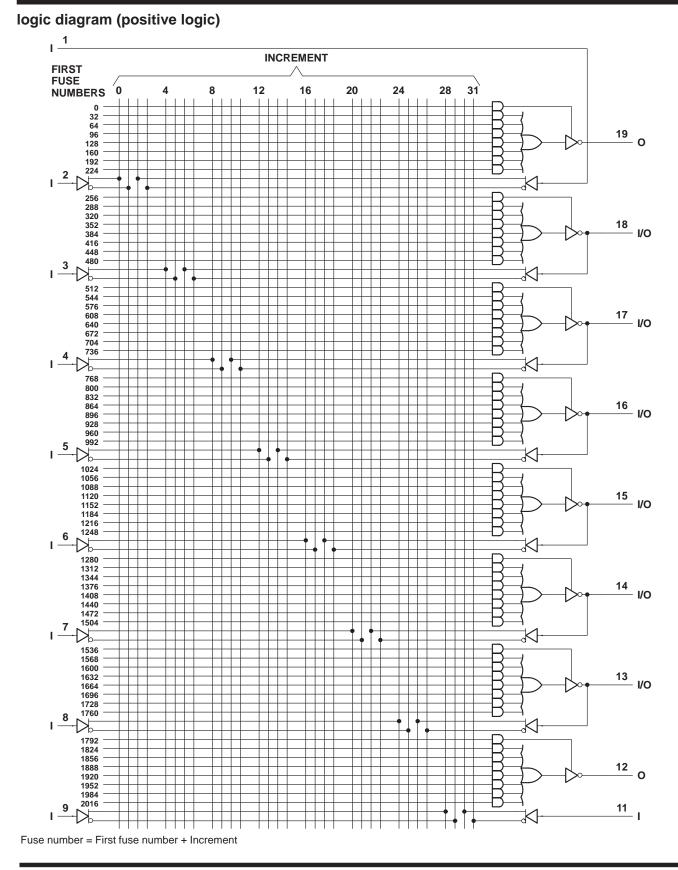
TIBPAL16R8'

8/ — Q 8 / 8

 \bigcirc denotes fused inputs



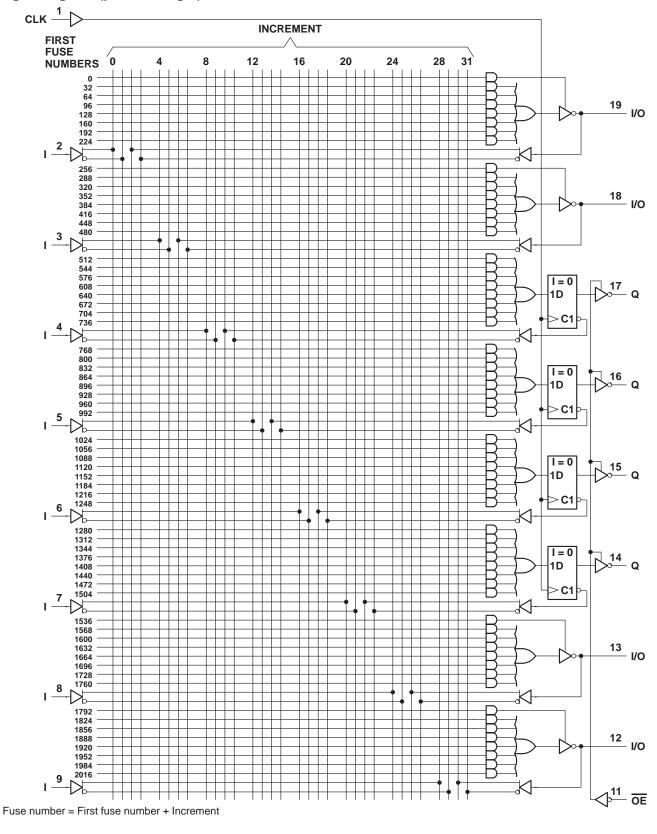
TIBPAL16L8-5C TIBPAL16L8-7M HIGH-PERFORMANCE IMPACT-XTM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992





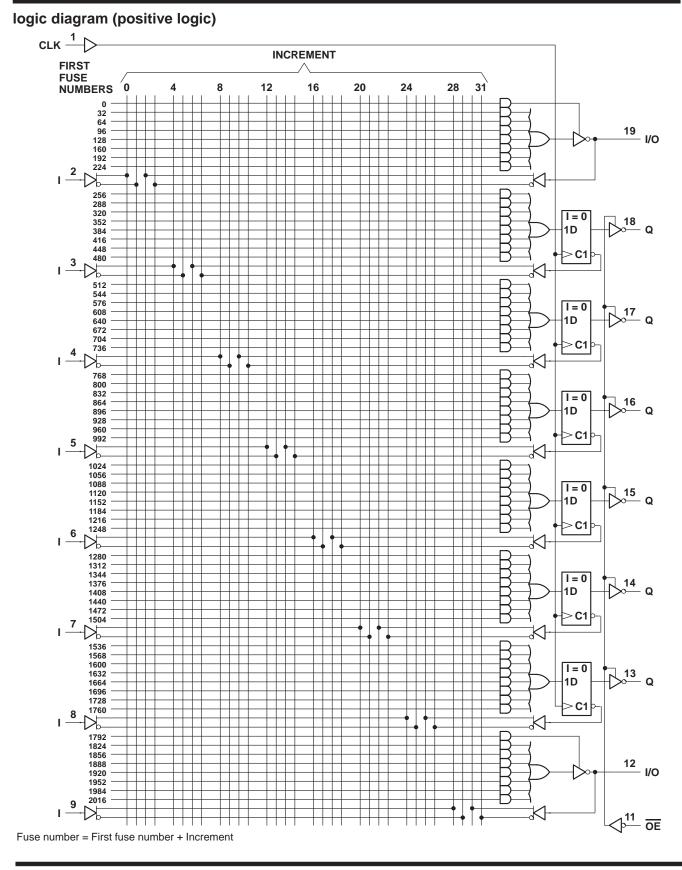
TIBPAL16R4-5C TIBPAL16R4-7M HIGH-PERFORMANCE IMPACT-X TM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

logic diagram (positive logic)





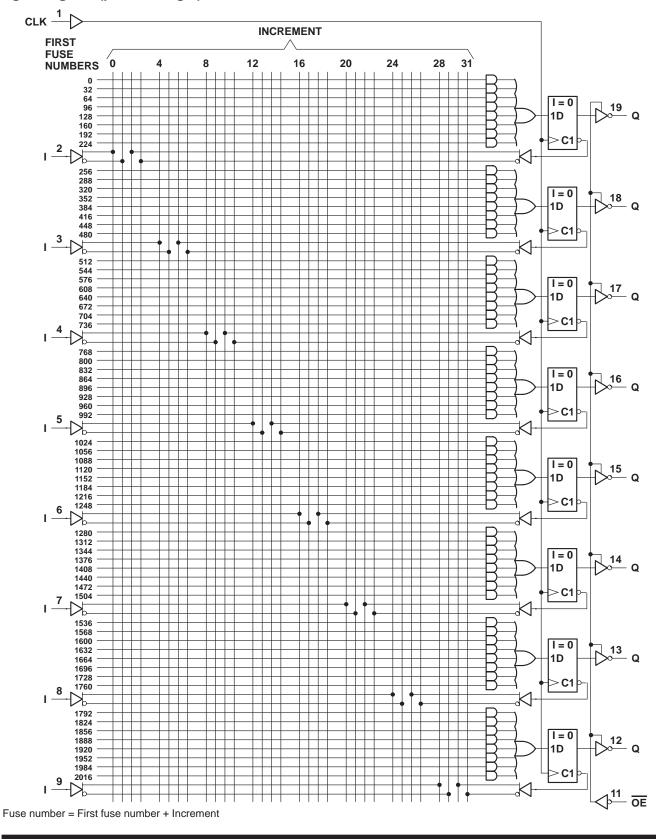
TIBPAL16R6-5C TIBPAL16R6-7M HIGH-PERFORMANCE IMPACT-XTM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992





TIBPAL16R8-5C TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X TM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

logic diagram (positive logic)





SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	-65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage (see Note 2)	2		5.5	V
VIL	Low-level input voltage (see Note 2)			0.8	V
ЮН	High-level output current			-3.2	mA
IOL	Low-level output current			24	mA
TA	Operating free-air temperature	0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
VIK	V _{CC} = 4.75 V,	lj = -18 mA			-0.8	-1.5	V
VOH	V _{CC} = 4.75 V,	I _{OH} = -3.2 mA		2.4	2.7		V
V _{OL}	V _{CC} = 4.75 V,	I _{OL} = 24 mA			0.3	0.5	V
IOZH [‡]	V _{CC} = 5.25 V,	$V_{O} = 2.7 V$				100	μA
I _{OZL} ‡	V _{CC} = 5.25 V,	$V_{O} = 0.4 V$				-100	μΑ
Ц	V _{CC} = 5.25 V,	V _I = 5.5 V				100	μΑ
IIH‡	V _{CC} = 5.25 V,	V _I = 2.7 V				25	μΑ
IIL‡	V _{CC} = 5.25 V,	VI = 0.4 V				-250	μA
IOS§	V _{CC} = 5.25 V,	$V_{O} = 0.5 V$		-30	-70	-130	mA
Icc	V _{CC} = 5.25 V,	V _I = 0,	Outputs open			180	mA
C _i	f = 1 MHz,	V ₁ = 2 V			8.5		pF
Co	f = 1 MHz,	$V_{O} = 2 V$			10		pF

electrical characteristics over recommended operating free-air temperature range

[†] All typical values are at V_{CC} = 5 V, $T_A = 25^{\circ}C$.

[‡] I/O leakage is the worst case of I_{OZL} and I_{IL} or I_{OZH} and I_{IH}, respectively.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. Vo is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM TO		TEST	TIBPAL16L8-5CFN		TIBPAI TIBPAI	UNIT		
	(INPUT)	(OUTPUT)		CONDITIONS	MIN	MAX	MIN	MAX	
	I, I/O	0, I/0	with up to 4 outputs switching		1.5	5	1.5	5	
^t pd	I, I/O	0, I/0	with more than 4 outputs switching	R1 = 200 Ω, R2 = 200 Ω,	1.5	5	1.5	5.5	ns
t _{en}	I, I/O	0, I/0		See Figure 8	2	7	2	7	ns
^t dis	I, I/O		0, I/O		2	7	2	7	ns

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



TIBPAL16R4-5C, TIBPAL16R6-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	. −65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.75	5	5.25	V
VIH	High-level input voltage (see Note 2)		2		5.5	V
VIL	Low-level input voltage (see Note 2)				0.8	V
ЮН	High-level output current				-3.2	mA
IOL	Low-level output current				24	mA
fclock	Clock frequency		0		125	MHz
+	Pulse duration, clock	High	4			ns
^t w		Low	4			115
t _{su}	Setup time, input or feedback before clock \uparrow	-	4.5			ns
t _h	Hold time, input or feedback after ${\sf clock} \uparrow$		0			ns
TA	Operating free-air temperature		0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.



TIBPAL16R4-5C, TIBPAL16R6-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

electrical characteristics over recommended operating free-air temperature range

PAR	AMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT	
VIK		V _{CC} = 4.75 V,	lj = -18 mA			-0.8	-1.5	V	
VOH		V _{CC} = 4.75 V,	I _{OH} = -3.2 mA		2.4	2.7		V	
V _{OL}		V _{CC} = 4.75 V,	I _{OL} = 24 mA			0.3	0.5	V	
IOZH‡		V _{CC} = 5.25 V,	V _O = 2.7 V				100	μΑ	
IOZL [‡]		V _{CC} = 5.25 V,	$V_{O} = 0.4 V$				-100	μΑ	
Ц		V _{CC} = 5.25 V,	V _I = 5.5 V				100	μΑ	
IIH‡		V _{CC} = 5.25 V,	V _I = 2.7 V				25	μΑ	
IIL‡		V _{CC} = 5.25 V,	V _I = 0.4 V				-250	μΑ	
IOS§		V _{CC} = 5.25 V,	V _O = 0.5 V		-30	-70	-130	mA	
ICC		V _{CC} = 5.25 V,	$V_{I} = 0,$	Outputs open			200	mA	
Ci	1	f = 1 MHz,	V _I = 2 V			7		pF	
	CLK/OE	1 – 1 IVII IZ,	v] - 2 v			5			
6	I/O	f = 1 MHz,	$\lambda = 2 \lambda$			10		ъĘ	
Co	Q	$I = I IVI \Box Z,$	vO = 2 v	$V_{O} = 2 V$		7		рF	

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM TO (INPUT) (OUTPUT)		TEST CONDITIONS	TIBPAL16R4-5CFN TIBPAL16R6-5CFN			TIBPAL16R4-5CJ TIBPAL16R6-5CJ TIBPAL16R4-5CN TIBPAL16R6-5CN			UNIT
				MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	
	withou	t feedback		125			125			
f _{max} ¶	with internal feedbac	k (counter configuration)		125			125			MHz
	with external feedback			117			111			
^t pd	CLK↑	Q		1.5		4	1.5		4.5	ns
^t pd	CLK↑	Internal feedback	R1 = 200 Ω,			3.5			3.5	ns
^t pd	I, I/O	I/O	R2 = 200 Ω,	1.5		5	1.5		5	ns
t _{en}	OE↓	Q	See Figure 8	1.5		6	1.5		6	ns
^t dis	OE↑	Q		1		6.5	1		7	ns
t _{en}	I, I/O	I/O		2		7	2		7	ns
t _{dis}	I, I/O	I/O		2		7	2		7	ns
tr					1.5			1.5		ns
tf					1.5			1.5		ns
^t sk(o) [#]	Skew between	registered outputs			0.5			0.5		ns

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

[‡] I/O leakage is the worst case of IOZL and IIL or IOZH and IIH, respectively.

 \P See 'f_{max} Specification' near the end of this data sheet.

 $# t_{sk(0)}$ is the skew time between registered outputs.



S Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

TIBPAL16R8-5C HIGH-PERFORMANCE *IMPACT-X* ™ *PAL*[®] CIRCUITS

SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	-65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.75	5	5.25	V
VIH	High-level input voltage (see Note 2)		2		5.5	V
VIL	Low-level input voltage (see Note 2)				0.8	V
ЮН	High-level output current				-3.2	mA
IOL	Low-level output current				24	mA
fclock	Clock frequency		0		125	MHz
		High	4			20
τ _W	Pulse duration, clock	Low	4			ns
t _{su}	Setup time, input or feedback before clock \uparrow	-	4.5			ns
t _h	Hold time, input or feedback after ${\sf clock} \uparrow$		0			ns
TA	Operating free-air temperature		0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.



TIBPAL16R8-5C HIGH-PERFORMANCE IMPACT-X™ PAL® CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

TIBPAL16R8-5CJ TIBPAL16R8-5CN TIBPAL16R8-5CFN PARAMETER **TEST CONDITIONS** UNIT TYP[†] MIN TYP[†] MIN MAX MAX VIK V_{CC} = 4.75 V, -0.8 -1.5 -0.8 -1.5 V $I_{I} = -18 \text{ mA}$ V $V_{CC} = 4.75 V,$ $I_{OH} = -3.2 \text{ mA}$ 2.7 2.7 2.4 2.4 VOH $V_{CC} = 4.75 V,$ $I_{OL} = 24 \text{ mA}$ 0.3 0.5 0.3 V VOL 0.5 $V_{CC} = 5.25 \overline{V},$ $V_{O} = 2.7 V$ 100 100 IOZH μΑ V_{CC} = 5.25 V, $V_{O} = 0.4 V$ -100 -100 μΑ IOZL $V_{CC} = 5.25 V,$ VI = 5.5 V 100 100 μA Ιį. $V_{I} = 2.7 V$ 25 25 Iн VCC = 5.25 V, μA V_{CC} = 5.25 V, $V_{I} = 0.4 V$ -250 -250 μA ΙIL los‡ $V_{CC} = 5.25 V_{,}$ $V_{0} = 0.5 V$ -30-70 -130 -30-70 -130 mΑ 180 180 V_{CC} = 5.25 V, mΑ $V_{I} = 0,$ Outputs open ICC 8.5 6.5 pF Ci f = 1 MHz, $V_I = 2 V$ CLK/OE 7.5 5.5 Co f = 1 MHz, $V_{O} = 2 V$ 10 8 pF

electrical characteristics over recommended operating free-air temperature range

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM TO (INPUT) (OUTPUT)		TEST CONDITIONS	TIBPAL16R8-5CFN			TIBPAL16R8-5CJ TIBPAL16R8-5CN			UNIT	
	(INPUT)	(INPUT) (OUTPUT)		CONDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	
	without feedback				125			125			
f _{max} §	with internal fe	edback (counter configuration)		125			125			MHz
	with external feedback				117			111			
	CLK↑	Q	with up to 4 outputs switching	R1 = 200 Ω,	1.5		4	1.5		4	
^t pd	CLK↑	Q	with more than 4 outputs switching	R2 = 200 Ω, See Figure 8	1.5		4	1.5		4.5	ns
t _{pd} ¶	CLK↑	li	nternal feedback				3.5			3.5	ns
t _{en}	OE↓		Q		1.5		6	1.5		6	ns
^t dis	OE↑		Q		1		6.5	1		7	ns
tr						1.5			1.5		ns
tf						1.5			1.5		ns
^t sk(o) [#]	Ske	ew betwe	en outputs			0.5			0.5		ns

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡]Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

§ See 'fmax Specification' near the end of this data sheet.

This parameter is calculated from the measured fmax with internal feedback in a counter configuration (see Figure 2 for illustration).

 $^{\#}$ t_{sk(0)} is the skew time between registered outputs.



TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	. −55°C to 125°C
Storage temperature range	. −65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		4.5	5	5.5	V
VIH	High-level input voltage (see Note 2)		2		5.5	V
VIL	Low-level input voltage (see Note 2)				0.8	V
IOH	High-level output current				-2	mA
IOL	Low-level output current				12	mA
f _{clock} †	Clock frequency				100	MHz
. +	Delas duration de la	High	5			ns
tw†	Pulse duration, clock	Low	5			115
t _{su} †	Setup time, input or feedback before clock $\hat{1}$					ns
th‡	Hold time, input or feedback after clock \uparrow					ns
TA	Operating free-air temperature			25	125	°C

 † f_{clock}, t_w, t_{su}, and t_h do not apply to TIBPAL16L8'

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.



TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X™ PAL® CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

electrical characteristics over recommended operating free-air temperature range

PA	RAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
VIK		V _{CC} = 4.5 V,	lj = -18 mA			-0.8	-1.5	V
VOH		V _{CC} = 4.5 V,	$I_{OH} = -2 \text{ mA}$		2.4	2.7		V
VOL		V _{CC} = 4.5 V,	I _{OL} = 12 mA			0.25	0.5	V
IOZH	0, Q outputs	V _{CC} = 5.5 V,					20	
'OZH	I/O ports	VCC = 0.5 V,	VO = 2.7 V	$V_{O} = 2.7 V$				μΑ
IOZL	0, Q outputs	V _{CC} = 5.5 V,	V _O = 0.4 V	Vo - 0.4 V			-20	μA
-OZL	I/O ports	VCC = 0.0 V,	VO = 0.4 V			-250		μΛ
l		V _{CC} = 5.5 V,	V _I = 5.5 V				1	mA
IН	I/O ports	V _{CC} = 5.5 V,	V ₁ = 2.7 V				100	μA
Π	All others		v - 2.7 v	v - 2.7 v			25	μΛ
۱ _{IL}		V _{CC} = 5.5 V,	$V_{I} = 0.4 V$				-250	μΑ
los‡		V _{CC} = 5.5 V,	$V_{O} = 0.5 V$		-30	-70	-130	mA
ICC		V _{CC} = 5.5 V,	$V_I = GND, \overline{OE} = V_{IH},$	Outputs open			210	mA
	1	f = 1 MHz,	VI = 2 V			8.5		pF
Ci	CLK/OE	I = I IVIIZ,	v _l = z v			7.5		P1
Co		f = 1 MHz,	$V_{O} = 2 V$			10		pF

[†] All typical values are at V_{CC} = 5 V, $T_A = 25^{\circ}$ C.

[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	MAX	UNIT
	without f	eedback		100		
f _{max} §	with internal feedback (counter configuration)			100		MHz
	with externa	al feedback	R1 = 390 Ω,	74		
^t pd	I, I/O	O, I/O	R2 = 750 Ω,	1	7	ns
^t pd	CLK	Q	See Figure 8	1	7	ns
t _{en}	OE↓	Q]	1	8	ns
^t dis	OE↑	Q]	1	10	ns
t _{en}	I, I/O	O, I/O]	1	9	ns
^t dis	I, I/O	O, I/O]	1	10	ns

§ See 'fmax Specification' near the end of this data sheet. fmax does not apply for TIBPAL16L8'. fmax with external feedback is not production tested and is calculated from the equation located in the fmax specifications section.



programming information

Texas Instruments programmable logic devices can be programmed using widely available software and inexpensive device programmers.

Complete programming specifications, algorithms, and the latest information on hardware, software, and firmware are available upon request. Information on programmers capable of programming Texas Instruments programmable logic is also available, upon request, from the nearest TI field sales office, local authorized TI distributor, or by calling Texas Instruments at (214) 997-5666.

asynchronous preload procedure for registered outputs (see Figure 1 and Note 3)[†]

The output registers can be preloaded to any desired state during device testing. This permits any state to be tested without having to step through the entire state-machine sequence. Each register is preloaded individually by following the steps given below.

- Step 1. With V_{CC} at 5 volts and Pin 1 at V_{IL} , raise Pin 11 to V_{IHH} .
- Step 2. Apply either V_{IL} or V_{IH} to the output corresponding to the register to be preloaded.
- Step 3. Lower Pin 11 to 5 V.
- Step 4. Remove output voltage, then lower Pin 11 to V_{IL}. Preload can be verified by observing the voltage level at the output pin.

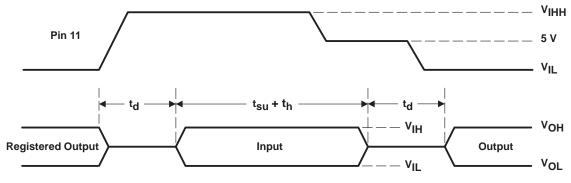


Figure 1. Asynchronous Preload Waveforms †

[†]Not applicable for TIBPAL16L8-5C and TIBPAL16L8-7M.

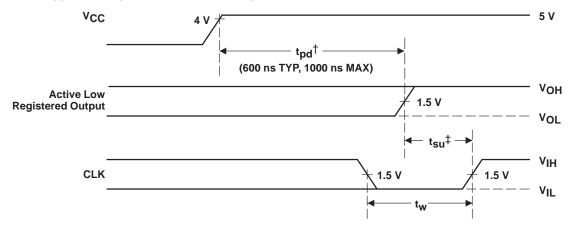
NOTE 3: $t_d = t_{SU} = t_h = 100 \text{ ns to } 1000 \text{ ns}$

VIHH = 10.25 V to 10.75 V



power-up reset (see Figure 2)

Following power up, all registers are reset to zero. This feature provides extra flexibility to the system designer and is especially valuable in simplifying state-machine initialization. To ensure a valid power-up reset, it is important that the rise of V_{CC} be monotonic. Following power-up reset, a low-to-high clock transition must not occur until all applicable input and feedback setup times are met.



[†] This is the power-up reset time and applies to registered outputs only. The values shown are from characterization data. [‡] This is the setup time for input or feedback.

Figure 2. Power-Up Reset Waveforms



fmax SPECIFICATIONS

f_{max} without feedback (see Figure 3)

In this mode, data is presented at the input to the flip-flop and clocked through to the Q output with no feedback. Under this condition, the clock period is limited by the sum of the data setup time and the data hold time $(t_{su} + t_h)$. However, the minimum fmax is determined by the minimum clock period $(t_w high + t_w low)$.

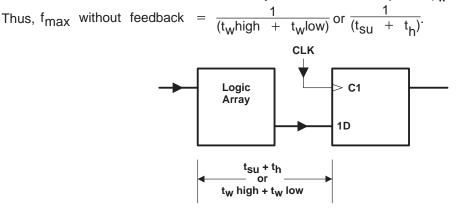


Figure 3. f_{max} Without Feedback

fmax with internal feedback (see Figure 4)

This configuration is most popular in counters and on-chip state-machine designs. The flip-flop inputs are defined by the device inputs and flip-flop outputs. Under this condition, the period is limited by the internal delay from the flip-flop outputs through the internal feedback and logic array to the inputs of the next flip-flop.

Thus,
$$f_{max}$$
 with internal feedback = $\frac{1}{(t_{su} + t_{pd} CLK - to - FB)}$.

Where tpd CLK-to-FB is the deduced value of the delay from CLK to the input of the logic array.

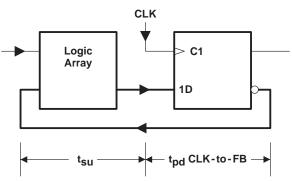


Figure 4. fmax With Internal Feedback



fmax SPECIFICATIONS

fmax with external feedback (see Figure 5)

This configuration is a typical state-machine design with feedback signals sent off-chip. This external feedback could go back to the device inputs or to a second device in a multi-chip state machine. The slowest path defining the period is the sum of the clock-to-output time and the input setup time for the external signals $(t_{su} + t_{pd} CLK-to-Q).$

Thus, f_{max} with external feedback =

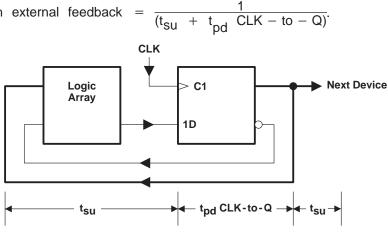


Figure 5. f_{max} With External Feedback



TIBPAL16R8-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

THERMAL INFORMATION

thermal management of the TIBPAL16R8-5C

Thermal management of the TIBPAL16R8-5CN and TIBPAL16R8-5CFN is necessary when operating at certain conditions of frequency, output loading, and outputs switching simultaneously. The device and system application will determine the appropriate level of management.

Determining the level of thermal management is based on factors such as power dissipation (P_D), ambient temperature (T_A), and transverse airflow (FPM). Figures 6 (a) and 6 (b) show the relationship between ambient temperature and transverse airflow at given power dissipation levels. The required transverse airflow can be determined at a particular ambient temperature and device power dissipation level in order to ensure the device specifications.

Figure 7 illustrates how power dissipation varies as a function of frequency and the number of outputs switching simultaneously. It should be noted that all outputs are fully loaded ($C_L = 50 \text{ pF}$). Since the condition of eight fully loaded outputs represents the worst-case condition, each application must be evaluated accordingly.

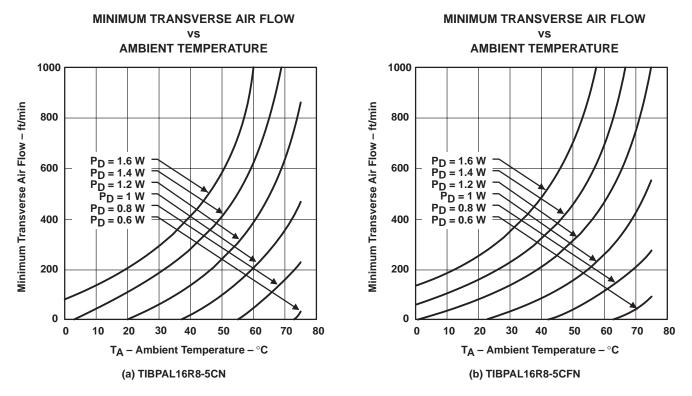


Figure 6



SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

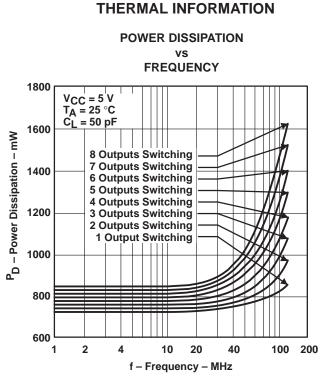
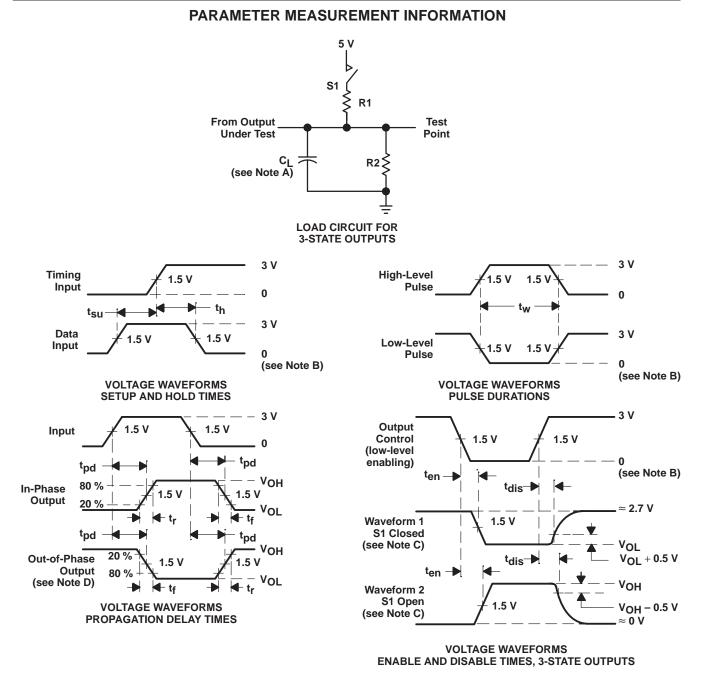


Figure 7



TIBPAL16L8-5C, TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-XTM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992



NOTES: A. CL includes probe and jig capacitance and is 50 pF for t_{pd} and t_{en} , 5 pF for t_{dis} .

- B. All input pulses have the following characteristics: For C suffix, PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%; For M suffix, PRR \leq 10 MHz, t_r = t_f \leq 2 ns, duty cycle = 50%
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. When measuring propagation delay times of 3-state outputs, switch S1 is closed.
- E. Equivalent loads may be used for testing.

Figure 8. Load Circuit and Voltage Waveforms



TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

metastable characteristics of TIBPAL16R4-5C, TIBPAL16R6-5C, and TIBPAL16R8-5C

At some point a system designer is faced with the problem of synchronizing two digital signals operating at two different frequencies. This problem is typically overcome by synchronizing one of the signals to the local clock through use of a flip-flop. However, this solution presents an awkward dilemma since the setup and hold time specifications associated with the flip-flop are sure to be violated. The metastable characteristics of the flip-flop can influence overall system reliability.

Whenever the setup and hold times of a flip-flop are violated, its output response becomes uncertain and is said to be in the metastable state if the output hangs up in the region between V_{IL} and V_{IH} . This metastable condition lasts until the flip-flop falls into one of its two stable states, which takes longer than the specified maximum propagation delay time (CLK to Q max).

From a system engineering standpoint, a designer cannot use the specified data sheet maximum for propagation delay time when using the flip-flop as a data synchronizer – how long to wait after the specified data sheet maximum must be known before using the data in order to guarantee reliable system operation.

The circuit shown in Figure 9 can be used to evaluate MTBF (Mean Time Between Failure) and Δt for a selected flip-flop. Whenever the Q output of the DUT is between 0.8 V and 2 V, the comparators are in opposite states. When the Q output of the DUT is higher than 2 V or lower than 0.8 V, the comparators are at the same logic level. The outputs of the two comparators are sampled a selected time (Δt) after system clock (SCLK). The exclusive OR gate detects the occurrence of a failure and increments the failure counter.

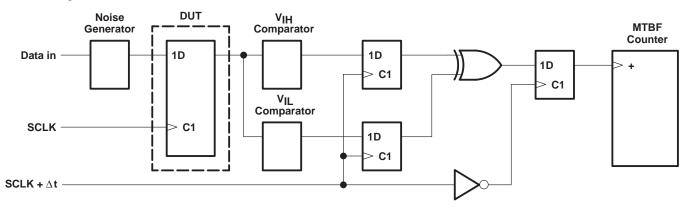


Figure 9. Metastable Evaluation Test Circuit

In order to maximize the possibility of forcing the DUT into a metastable state, the input data signal is applied so that it always violates the setup and hold time. This condition is illustrated in the timing diagram in Figure 10. Any other relationship of SCLK to data will provide less chance for the device to enter into the metastable state.

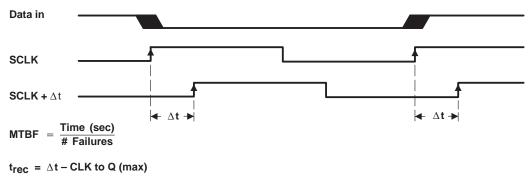


Figure 10. Timing Diagram



TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*[®] CIRCUITS

SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

By using the described test circuit, MTBF can be determined for several different values of Δt (see Figure 9). Plotting this information on semilog scale demonstrates the metastable characteristics of the selected flip-flop. Figure 11 shows the results for the TIBPAL16'-5C operating at 1 MHz.

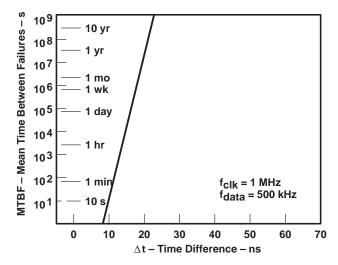


Figure 11. Metastable Characteristics

From the data taken in the above experiment, an equation can be derived for the metastable characteristics at other clock frequencies.

The metastable equation: $\frac{1}{\text{MTBF}} = f_{\text{SCLK}} \times f_{\text{data}} \times \text{C1} \text{ e} (-\text{C2} \times \Delta t)$

The constants C1 and C2 describe the metastable characteristics of the device. From the experimental data, these constants can be solved for: $C1 = 4.37 \times 10^{-3}$ and C2 = 2.01

Therefore

 $\frac{1}{\text{MTBF}}$ = f_{SCLK} x f_{data} x 4.37 x 10⁻³ e (-2.01 x Δt)

definition of variables

DUT (Device Under Test): The DUT is a 5-ns registered PLD programmed with the equation Q : = D.

MTBF (Mean Time Between Failures): The average time (s) between metastable occurrences that cause a violation of the device specifications.

fSCLK (system clock frequency): Actual clock frequency for the DUT.

f_{data} (data frequency): Actual data frequency for a specified input to the DUT.

C1: Calculated constant that defines the magnitude of the curve.

C2: Calculated constant that defines the slope of the curve.

 t_{rec} (metastability recovery time): Minimum time required to guarantee recovery from metastability, at a given MTBF failure rate. $t_{rec} = \Delta t - t_{pd}$ (CLK to Q, max)

∆t: The time difference (ns) from when the synchronizing flip-flop is clocked to when its output is sampled.

The test described above has shown the metastable characteristics of the TIBPAL16R4/R6/R8-5C series. For additional information on metastable characteristics of Texas Instruments logic circuits, please refer to TI Applications publication SDAA004, "Metastable Characteristics, Design Considerations for ALS, AS, and LS Circuits."



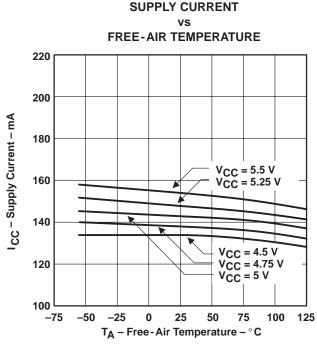
TIBPAL16L8-5C, TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X TM PAL[®] CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

LOW-LEVEL OUTPUT CURRENT **HIGH-LEVEL OUTPUT CURRENT** vs VS LOW-LEVEL OUTPUT VOLTAGE **HIGH-LEVEL OUTPUT VOLTAGE** 20 0 $V_{CC} = 5 V,$ $V_{CC} = 5 V,$ $T_A = 25 °C$ T_A = 25 ° C -10 15 I_{OH} – High-Level Output Current – mA I _{OL} – Low-Level Output Current – mA -20 10 -30 5 -40 -50 0 -60 -5 -70 -10 -80 -15 -90 -100 -20 -0.8 -0.6 -0.4 -0.2 0 0.2 0.4 0.6 0.8 0 0.5 1 1.5 2 2.5 3 VOL - Low-Level Output Voltage - V VOH - High-Level Output Voltage - V

TYPICAL CHARACTERISTICS

Figure 12

Figure 13





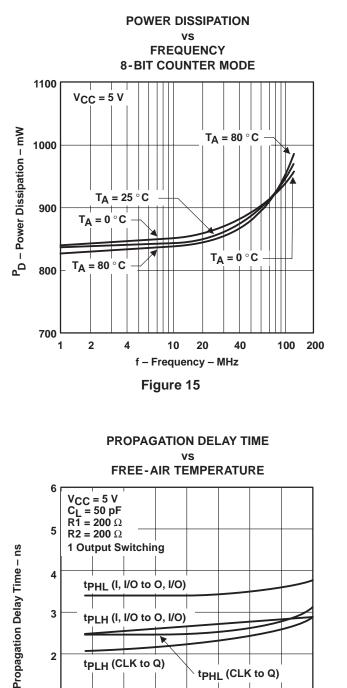


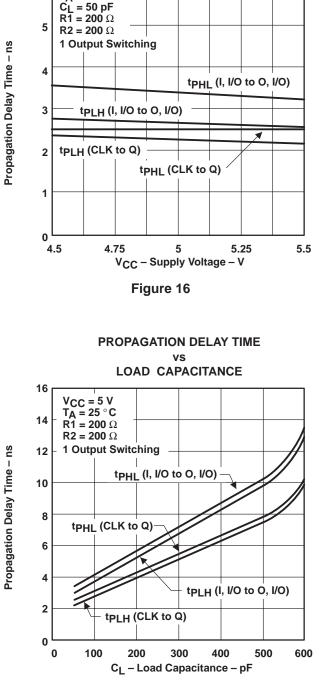
TIBPAL16L8-5C, TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X™ PAL[®] CIRCUITS SRPS011D - D3359, OCTOBER 1989 - REVISED SEPTEMBER 1992

TYPICAL CHARACTERISTICS

6

T_A = 25 ° C





PROPAGATION DELAY TIME

vs

SUPPLY VOLTAGE



0

25

T_A – Free - Air Temperature – ° C

50

t_{PHL} (CLK to Q)

75

100

125

tPHL (I, I/O to O, I/O)

tPLH (I, I/O to O, I/O)

t_{PLH} (CLK to Q)

4

3

2

1

0

-75 -50 -25

Figure 18

Texas 🐺 hic

TIBPAL16L8-5C, TIBPAL16R4-5C, TIBPAL16R6-5C, TIBPAL16R8-5C TIBPAL16L8-7M, TIBPAL16R4-7M, TIBPAL16R6-7M, TIBPAL16R8-7M HIGH-PERFORMANCE IMPACT-X TM PAL® CIRCUITS SRPS011D – D3359, OCTOBER 1989 – REVISED SEPTEMBER 1992

TYPICAL CHARACTERISTICS

Propagation Delay Time – ns

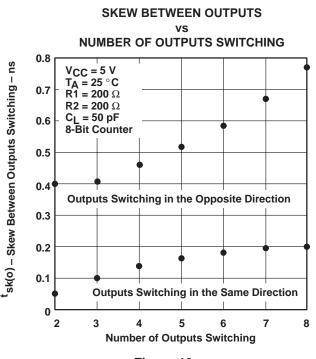


Figure 19

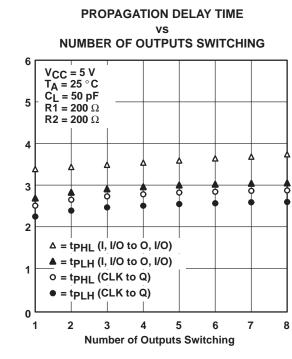


Figure 20



TI North Offices

ALABAMA: Huntsville: (205) 837-7530 ARIZONA: Phoenix: (602) 995-1007 CALIFORNIA: Irvine: (714) 660-1200 San Diego: (619) 278-9600 Santa Clara: (408) 980-9000 Woodland Hills: (818) 704-8100 COLORADO: Aurora: (303) 368-8000 CONNECTICUT: Wallingford: (203) 269-0074 FLORIDA: Altamonte Springs: (407) 260-2116 Fort Lauderdale: (305) 973-8502 Tampa: (813) 885-7588 GEORGIA: Norcross: (404) 662-7967 ILLINOIS: Arlington Heights: (708) 640-3000 INDIANA: Carmel: (317) 573-6400 Fort Wayne: (219) 489-4697 KANSAS: Overland Park: (913) 451-4511 MARYLAND: Columbia: (410) 964-2003 MASSACHUSETTS: Waltham: (617) 895-9100 MICHIGAN: Farmington Hills: (313) 553-1581 MINNESOTA: Eden Prairie: (612) 828-9300 MISSOURI: St. Louis: (314) 821-8400 NEW JERSEY: Iselin: (908) 750-1050 NEW MEXICO: Albuquerque: (505) 345-2555 NEW YORK: East Syracuse: (315) 463-9291 Fishkill: (914) 897-2900 Melville: (516) 454-6600 Pittsford: (716) 385-6770 NORTH CAROLINA: Charlotte: (704) 527-0930 Raleigh: (919) 876-2725 OHIO: Beachwood: (216) 765-7258 Beavercreek: (513) 427-6200 OREGON: Beaverton: (503) 643-6758 PENNSYLVANIA: Blue Bell: (215) 825-9500 PUERTO RICO: Hato Rey: (809) 753-8700 TEXAS: Austin: (512) 250-6769 Dallas: (214) 917-1264 Houston: (713) 778-6592 Midland: (915) 561-7137 UTAH: Salt Lake City: (801) 466-8972 WISCONSIN: Waukesha: (414) 798-1001 CANADA: Nepean: (613) 726-1970 Richmond Hill: (416) 884-9181 St. Laurent: (514) 335-8392

TI Regional Technology Centers

CALIFORNIA: Irvine: (714) 660-8140 Santa Clara: (408) 748-2222 GEORGIA: Norcross: (404) 662-7945 ILLINOIS: Arlington Heights: (708) 640-2909 INDIANA: Indianapolis: (317) 573-6400 MASSACHUSETTS: Waltham: (617) 895-9196 MEXICO: Mexico City: 491-70834 MINNESOTA: Minneapolis: (612) 828-9300 TEXAS: Dallas: (214) 917-3881 CANADA: Nepean: (613) 726-1970

Customer **Response Center**

TOLL FREE:	
OUTSIDE USA:	

(800) 336-5236 (214) 995-6611 (8:00 a.m. - 5:00 p.m. CST)

TI Authorized American Sales North American Distributors

Alliance Electronics, Inc. (military product only) Almac/Arrow Anthem Electronics Arrow/Schweber Future Electronics (Canada) GRS Electronics Co., Inc. Hall-Mark Electronics Marshall Industries Newark Electronics, Inc. (checklet product and w/ 600 Almac/Arrow (obsolete product only (508) 462-9332) Wyle Laboratories Zeus Components

TI Distributors

ALABAMA: Arrow/Schweber (205) 837-6955; Hall-Mark (205) 837-8700; Marshall (205) 881-9235.

(205) 837-8700; Marshall (205) 881-9235. **ARIZONA:** Anthem (602) 966-6600; Arrow/Schweber (602) 437-0750; Hall-Mark (602) 431-0030; Marshall (602) 496-0290; Wyle (602) 437-2088. **CALIFORNIA:** Los **Angeles/Orange County:** Anthem (818) 775-1333, (714) 768-4444; Arrow/Schweber (818) 380-9686, (714) 838-5422; Hall-Mark (818) 773-4500, (714) 727-6000; Marshall (818) 878-7000, (714) 458-5301; Wyle (818) 880-9000, (714) 863-9953; Zeus (714) 921-9000, (818) 880-93838; **Sacrament:** Anthem (916) 624-9744; Hall-Mark (916)

(616) 565-5555, Sacramento: Anthem (916) 624-9744; Hall-Mark (916) 624-9781; Marshall (916) 635-9700; Wyle (916) 638-5282; San Diego: Anthem (619) 453-9005; Arrow/Schweber (619) 565-4800; Hall-Mark (619) 268-1201; Marshall (619) 578-9600; Wyle (619) 565-9171; Zeus (619) 277-9681.

San Francisco Bay Area: Anthen (408) 453-1200; Arrow/Schweber (408) 441-9700, (510) 490-9477; Hall-Mark (408) 432-4000; Marshall (408) 942-4600; Wyle (408) 727-2500; Zeus (408) 629-4789.

(303) 799-0258; Hall-Mark (303) 790-4500; Arrow/Schweber (303) 799-0258; Hall-Mark (303) 790-1662; Marshall (303) 451-8383; Wyle (303) 457-9953.

CONNECTICUT: Anthem (203) 575-1575; Arrow/Schweber (203) 265-7741; Hall-Mark (203) 271-2844; Marshall (203) 265-3822.

FLORIDA: Fort Lauderdale: Arrow/Schweber (305) 429-8200; Halll-Mark (305) 971-9280; Marshall (305) 977-4990 977-4880.

Orlando: Arrow/Schweber (407) 333-9300; Hall-Mark (407) 830-5855; Marshall (407) 767-8585; Zeus (407) 788-9100. Tampa: Hall-Mark (813) 541-7440; Marshall (813) 573-1399.

GEORGIA: Arrow/Schweber (404) 497-1300; Hall-Mark (404) 623-4400; Marshall (404) 923-5750. (404) 525-4400, Marshall (404) 525-5750. ILLINOIS: Anthem (708) 884-0200; Arrow/Schweber (708) 250-0500; Hall-Mark (312) 880-3800; Marshall (708) 490-0155; Newark (312) 784-5100. INDIANA: Arrow/Schweber (317) 299-2071; Hall-Mark (317) 872-8875; Marshall (317) 297-0483.

IOWA: Arrow/Schweber (319) 395-7230.

KANSAS: Arrow/Schweber (913) 541-9542; Hall-Mark (913) 888-4747; Marshall (913) 492-3121. MARYLAND: Anthem (301) 995-6640; Arrow/Schweber (301) 596-7800; Hall-Mark (301) 988-9800; Marshall (301) 622-1118; Zeus (301) 997-1118.

MASSACHUSETTS: Anthem (508) 657-5170; Arrow/Schweber (508) 658-0900; Hall-Mark (508) 667-0902; Marshall (508) 658-0810; Wyle (617) 272-7300; Zourg (627) 046 0900; Zeus (617) 246-8200.

MICHIGAN: Detroit: Arrow/Schweber (313) 462-2290; Hall-Mark (313) 416-5800; Marshall (313) 525-5850; Newark (313) 967-0600.

MINNESOTA: Anthem (612) 944-5454; Arrow/Schweber (612) 941-5280; Hall-Mark (612) 881-2600; Marshall (612) 559-2211.

MISSOURI: Arrow/Schweber (314) 567-6888; Hall-Mark (314) 291-5350; Marshall (314) 291-4650.

(314) 291-5350; Marshall (314) 291-4650. **NEW JERSEY:** Anthem (201) 227-7960; Arrow/Schweber (201) 227-7880, (609) 596-8000; Hall-Mark (201) 515-3000, (609) 235-1900; Marshall (201) 882-0320, (609) 234-9100. **NEW MEXICO.** Alliance (505) 292-3360. **NEW YORK:** Long Island: Anthem (516) 864-6600; Arrow/Schweber (516) 231-1000; Hall-Mark (516) 737-0600; Marshall (516) 273-2424; Zeus (914) 937-7400. **Pacheoter:** Arrow/Schweber (716) 472-0300; Hall-Mark

Rochester: Arrow/Schweber (716) 427-0300; Hall-Mark (716) 425-3300; Marshall (716) 235-7620. Syracuse: Marshall (607) 785-2345.

NORTH CAROLINA: Arrow/Schweber (919) 876-3132; Hall-Mark (919) 872-0712; Marshall (919) 878-9882.

OHIO: Cleveland: Arrow/Schweber (216) 248-3990; Hall-Mark (216) 349-4632; Marshall (216) 248-1788. Columbus: Hall-Mark (614) 888-3313.

Dayton: Arrow/Schweber (513) 435-5563; Marshall (513) 898-4480; Zeus (513) 293-6162.

OKLAHOMA: Arrow/Schweber (918) 252-7537; Hall-Mark (918) 254-6110.

OREGON: Almac/Arrow (503) 629-8090; Anthem (503) 643-1114; Marshall (503) 644-5050; Wyle (503) 643-7900. p43-1114; Marshall (503) 644-5050; Wyle (503) 643-7000. **PENRSYLVANIA**: Anthem (215) 443-5150; Arrow/Schweber (215) 928-1800; GRS (215) 922-7037; (609) 964-8560; Marshall (412) 788-0441. **TEXAS: Austin:** Arrow/Schweber (512) 835-4180; Hall-Mark (512) 258-8848; Marshall (512) 837-1991; Wyle (512) 345-8853;

 Dallas: Anthem (214) 238-7100; Arrow/Schweber (214) 380-6464; Hall-Mark (214) 553-4300; Marshall (214) 233-5200; Wyle (214) 235-9953; Zeus (214) 783-7010; Houston: Arrow/Schweber (713) 530-4700; Hall-Mark (713) 781-6100; Marshall (713) 467-1666; Wyle (713) 879-9953.

UTAH: Anthem (801) 973-8555; Arrow/Schweber (801) 973-6913; Marshall (801) 973-2288; Wyle (801) 974-9953. **WASHINGTON:** Almac/Arrow (206) 643-9992, Anthem (206) 483-1700; Marshall (206) 486-5747; Wyle (206) 881-1150.

WISCONSIN: Arrow/Schweber (414) 792-0150; Hall-Mark (414) 797-7844; Marshall (414) 797-8400. CANADA: Calgary: Future (403) 235-5325;

Edmonton: Future (403) 438-2858

Montreal: Arrow/Schweber (514) 421-7411; Future (514) 694-7710; Marshall (514) 694-8142 Ottawa: Arrow/Schweber (613) 226-6903; Future (613)

820-8313 Quebec: Future (418) 897-6666.

Toronto: Arrow/Schweber (416) 670-7769; Future (416) 612-9200; Marshall (416) 458-8046. Vancouver: Arrow/Schweber (604) 421-2333; Future (604) 294-1166.

TI Die Processors

Chip Supply Elmo Semiconductor Minco Technology Labs

(407) 298-7100 (818) 768-7400 (512) 834-2022

INSTRUMENTS

D0892



PACKAGE OPTION ADDENDUM

4-Mar-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
5962-85155212A	ACTIVE	LCCC	FK	20	1	None	Call TI	Level-NC-NC-NC
5962-8515521RA	ACTIVE	CDIP	J	20	1	None	Call TI	Level-NC-NC-NC
5962-8515521SA	ACTIVE	CFP	W	20	1	None	Call TI	Level-NC-NC-NC
5962-85155222A	ACTIVE	LCCC	FK	20	1	None	Call TI	Level-NC-NC-NC
5962-8515522RA	ACTIVE	CDIP	J	20	1	None	Call TI	Level-NC-NC-NC
5962-8515522SA	ACTIVE	CFP	W	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16L8-5CFN	OBSOLETE	PLCC	FN	20		None	Call TI	Call TI
TIBPAL16L8-5CN	OBSOLETE	PDIP	Ν	20		None	Call TI	Call TI
TIBPAL16R4-5CFN	ACTIVE	PLCC	FN	20	46	None	Call TI	Level-1-220-UNLIM
TIBPAL16R4-5CN	NRND	PDIP	Ν	20	20	None	Call TI	Level-NC-NC-NC
TIBPAL16R4-7MFKB	ACTIVE	LCCC	FK	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16R4-7MJB	ACTIVE	CDIP	J	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16R4-7MWB	ACTIVE	CFP	W	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16R6-5CFN	ACTIVE	PLCC	FN	20	46	None	Call TI	Level-1-220-UNLIM
TIBPAL16R6-5CN	ACTIVE	PDIP	Ν	20	20	None	Call TI	Level-NC-NC-NC
TIBPAL16R8-5CFN	ACTIVE	PLCC	FN	20	46	None	Call TI	Level-1-220-UNLIM
TIBPAL16R8-5CN	ACTIVE	PDIP	Ν	20	20	None	Call TI	Level-NC-NC-NC
TIBPAL16R8-7MFKB	ACTIVE	LCCC	FK	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16R8-7MJB	ACTIVE	CDIP	J	20	1	None	Call TI	Level-NC-NC-NC
TIBPAL16R8-7MWB	ACTIVE	CFP	W	20	1	None	Call TI	Level-NC-NC-NC

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

None: Not yet available Lead (Pb-Free).

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright © 2005, Texas Instruments Incorporated